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ASA-1236

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Y. KOMIYA, et al.

Serial No.: 10/533,127 ✓

Filed: April 29, 2005

For: DEFECT ANALYSIS APPARATUS, SYSTEM AND METHOD
FOR SEMICONDUCTOR INTEGRATED CIRCUIT

Group: 2858

Examiner: V. Q. Nguyen

RESPONSE TO RESTRICTION REQUIREMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

October 22, 2007

Sir:

The following is in response to the October 10, 2007 Office Action in which the Examiner alleges that restriction under 35 USC §121 is required and requested Applicants to elect one of the alleged inventions.

In response to the restriction requirement Applicants hereby elect without traverse invention Group I, claims 1-13 and 15-17 for further prosecution on the merits. Accordingly, an Office Action examining claims 1-13 and 15-17 is respectfully requested.